

OptiMOS™-5 Power-Transistor





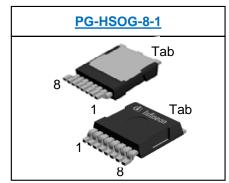
Features

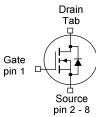
- N-channel Enhancement mode
- AEC qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green product (RoHS compliant)
- Ultra low Rds(on)
- 100% Avalanche tested

Туре	Package	Marking	
IAUS300N08S5N012	PG-HSOG-8-1	A08S5N12	

Product Summary

V _{DS}	80	V
R _{DS(on)}	1.2	mΩ
I _D	300	Α





Maximum ratings, at T_j =25 °C, unless otherwise specified

Continuous drain current	ID	$T_{\rm C}$ =25°C, $V_{\rm GS}$ =10 $V^{1)}$	300	Α
		T _C =100 °C, V _{GS} =10 V ²⁾	300	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25 °C	1200	
Avalanche energy, single pulse ²⁾	E _{AS}	I _D =150 A	817	mJ
Avalanche current, single pulse	I _{AS}	-	300	А
Gate source voltage	V_{GS}	-	±20	V
Power dissipation	P_{tot}	T _C =25 °C	375	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-	-55 + 175	°C
IEC climatic category; DIN IEC 68-1	-	-	55/175/56	



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R_{thJC}	-	-	-	0.4	K/W

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage ²⁾	V _{(BR)DSS}	V _{GS} =0 V, I _D =1 mA	80	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 275 \mu {\rm A}$	2.2	3	3.8	
		V_{DS} =50 V, V_{GS} =0 V, T_{j} =85 °C ²⁾	1	1	20	
Gate-source leakage current	I _{GSS}	V_{GS} =20 V, V_{DS} =0 V		1	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =6 V, I _D =75 A	-	1.3	1.7	mΩ
		V _{GS} =10 V, I _D =100 A	-	1.0	1.2	



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance	Ciss		-	12500	16250	pF
Output capacitance	Coss	V_{GS} =0 V, V_{DS} =40 V, f =1 MHz	-	2000	2600	
Reverse transfer capacitance	C _{rss}		-	86	130	
Turn-on delay time	t _{d(on)}		-	31	-	ns
Rise time	t _r	V _{DD} =40 V, V _{GS} =10 V,	-	19	-	
Turn-off delay time	$t_{\text{d(off)}}$	$I_{\rm D}$ =100 A, $R_{\rm G}$ =3.5 Ω	-	69	-	
Fall time	t _f		-	55	-	
Gate Charge Characteristics ²⁾						
Gate to source charge	Q _{gs}		-	56	73	nC
Gate charge total	Qg	V _{DD} =40 V, I _D =100 A, V _{GS} =0 to 10 V	-	178	231	1
Gate plateau voltage	V _{plateau}		-	4.5	-	V
Reverse Diode	•					
Diode continous forward current ²⁾	Is	- T _C =25 °C	-	-	300	А
Diode pulse current ²⁾	I _{S,pulse}		-	-	1200	
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =100 A, T _j =25 °C	-	0.9	1.2	V
Reverse recovery time ²⁾	t _{rr}	V _R =40 V, I _F =50A, di _F /dt=100 A/μs	-	86	-	ns
Reverse recovery charge ²⁾	Q _{rr}		-	177	-	nC

 $^{^{1)}}$ Current is limited by bondwire; with an $R_{\rm thJC}$ = 0.4 K/W the chip is able to carry 400A at 25°C.

²⁾ Defined by design. Not subject to production test.



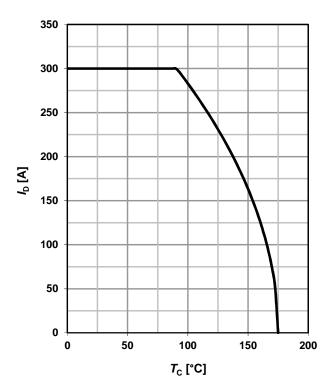
1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \ge 6 \text{ V}$$

300 200 100 100 T_C [°C]

2 Drain current

$$I_D = f(T_C); V_{GS} \ge 6 \text{ V}$$



3 Safe operating area

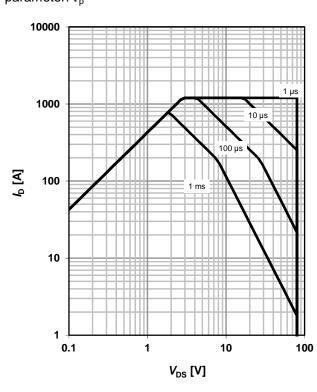
$$I_D = f(V_{DS}); T_C = 25 \text{ °C}; D = 0$$

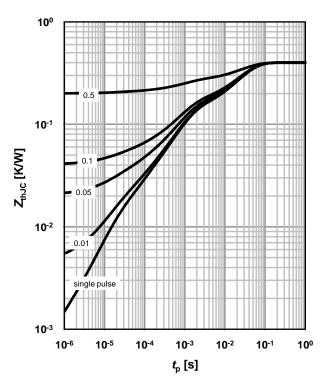
parameter: t_p

4 Max. transient thermal impedance

$$Z_{thJC} = f(t_p)$$

parameter: $D=t_p/T$







5 Typ. output characteristics

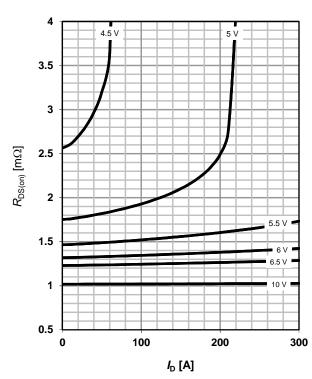
 $I_D = f(V_{DS}); T_j = 25 \text{ °C}$

parameter: $V_{\rm GS}$

6 Typ. drain-source on-state resistance

 $R_{DS(on)} = (I_D); T_j = 25 \text{ °C}$

parameter: $V_{\rm GS}$

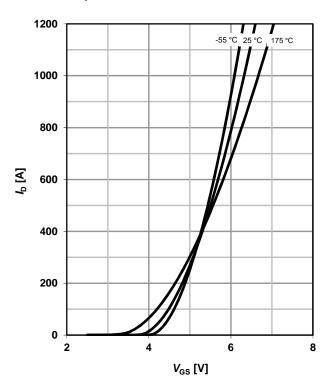


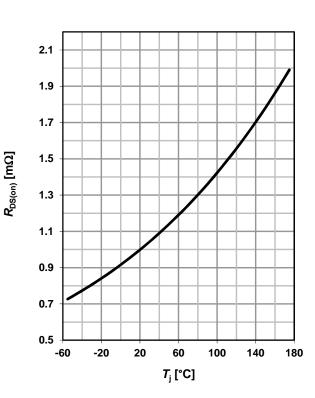
7 Typ. transfer characteristics

 $I_D = f(V_{GS}); V_{DS} = 6V$

parameter: T_j

8 Typ. drain-source on-state resistance $R_{DS(on)} = f(T_j)$; $I_D = 100 \text{ A}$; $V_{GS} = 10 \text{ V}$







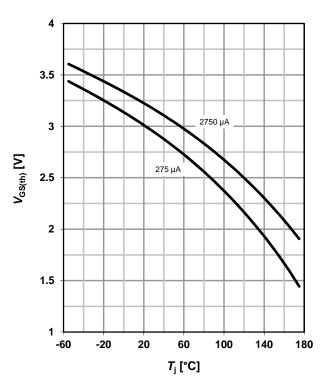
9 Typ. gate threshold voltage

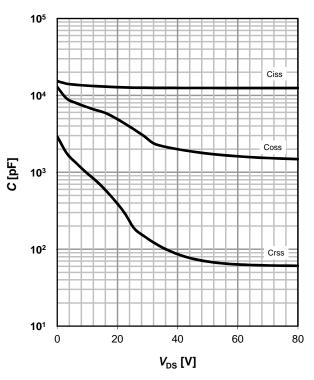
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D

10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$





11 Typical forward diode characteristicis

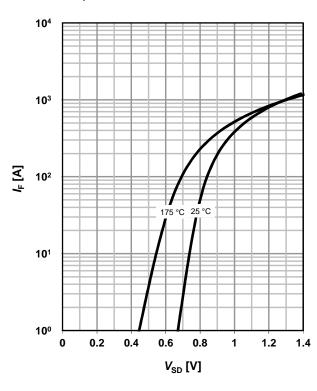
 $IF = f(V_{SD})$

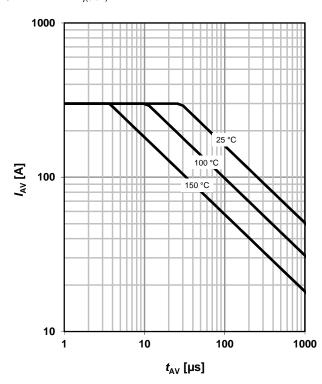
parameter: T_i

12 Typ. avalanche characteristics

 $I_{AS} = f(t_{AV})$

parameter: T_{j(start)}







13 Typical avalanche energy

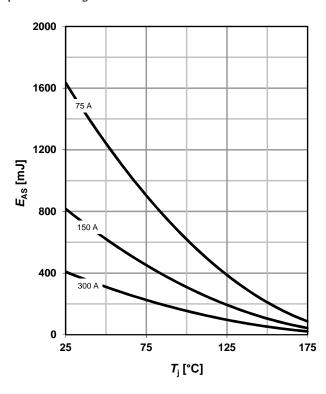
 $E_{AS} = f(T_i)$

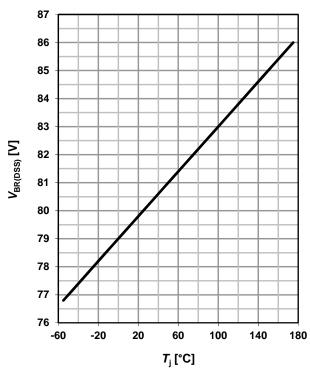
parameter: I_D

14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_j); I_{D_{typ}} = 1 \text{ mA}$$

16 Gate charge waveforms

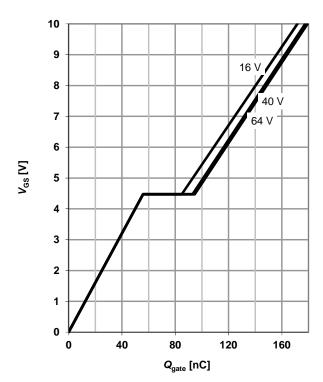


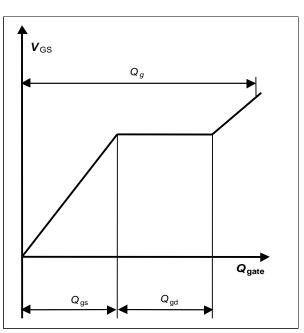


15 Typ. gate charge

 $V_{GS} = f(Q_{gate}); I_D = 300 A pulsed$

parameter: V_{DD}







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Revision History

Version	Date	Changes
Version 1.0	10.04.2018	Final Datasheet
Version 1.1	04.05.2020	Modified package name
Version 1.2	16.05.2022	Modified diagram 5 (page 5)